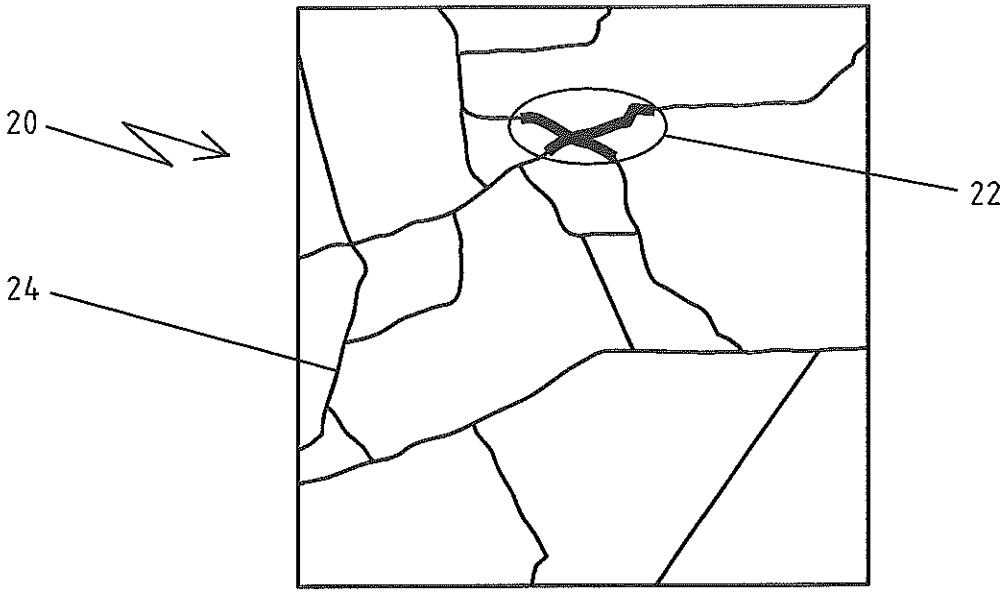


Fig. 1
(Prior art)

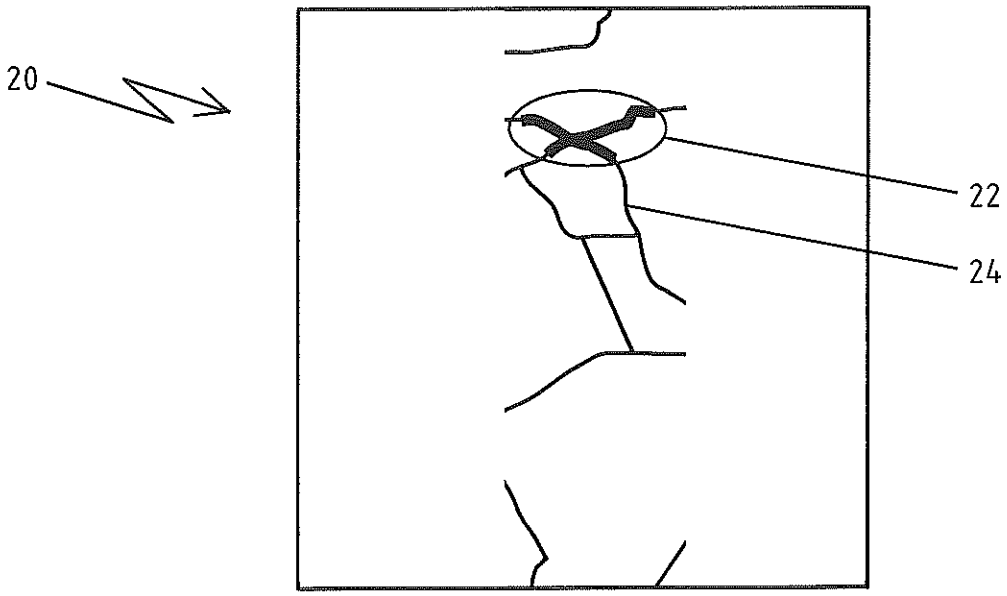


Fig. 2

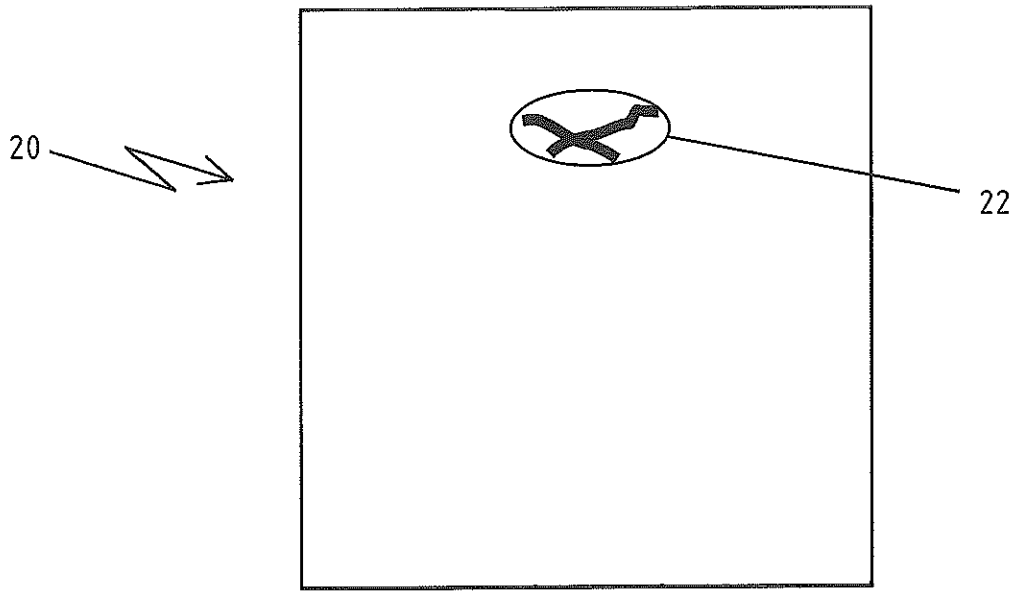

20
22

Fig. 3

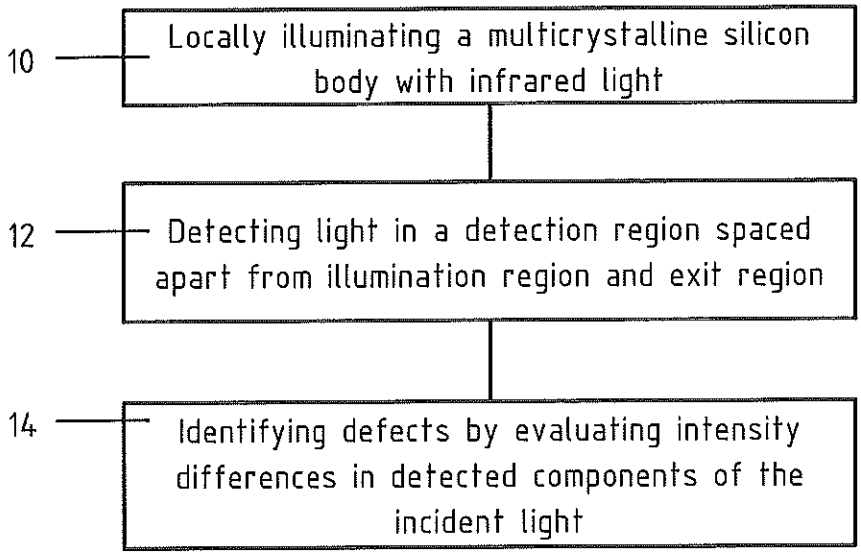

10
Locally illuminating a multicrystalline silicon body with infrared light
12
Detecting light in a detection region spaced apart from illumination region and exit region
14
Identifying defects by evaluating intensity differences in detected components of the incident light

Fig. 4

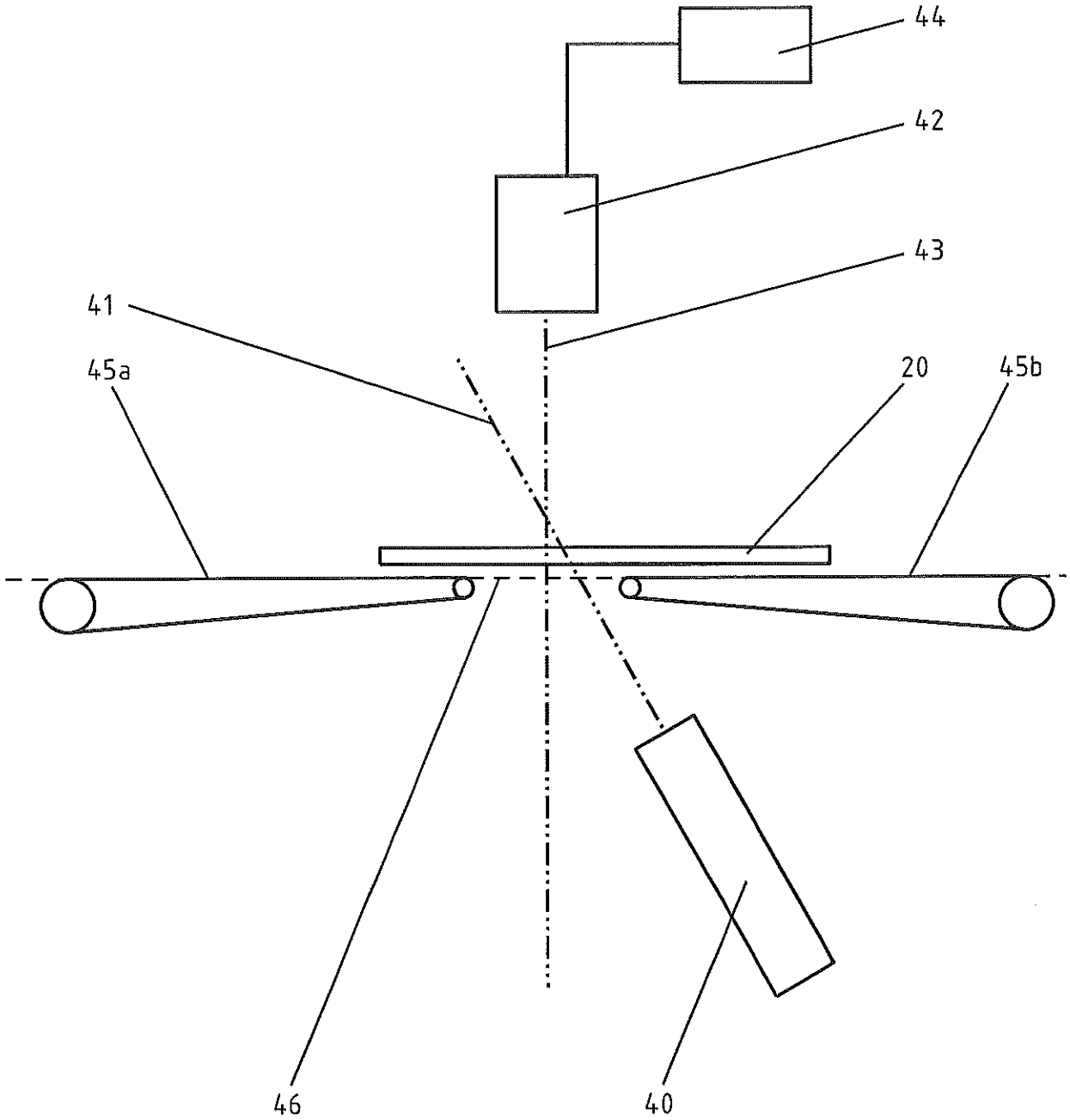


Fig. 5

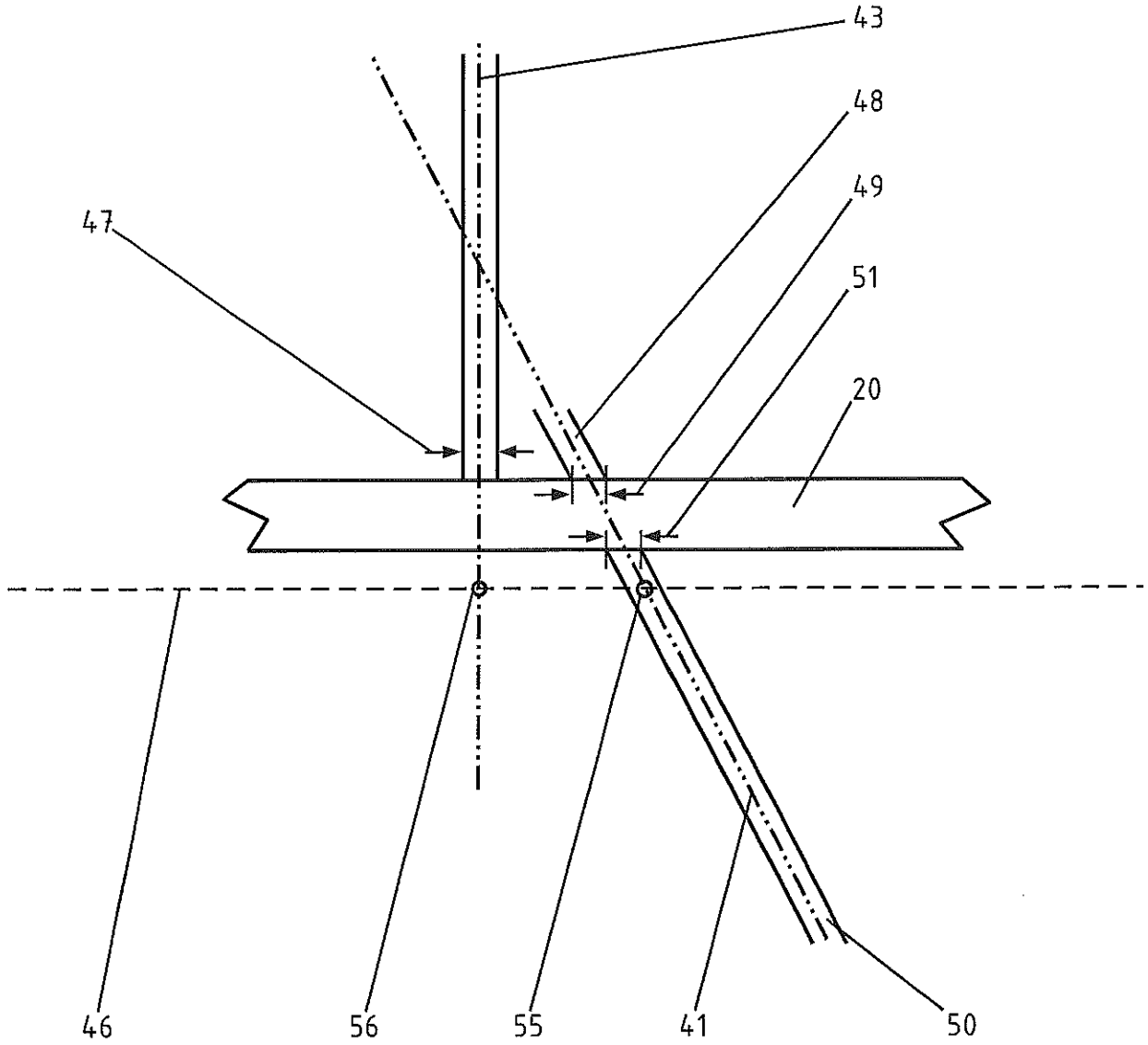


Fig. 6

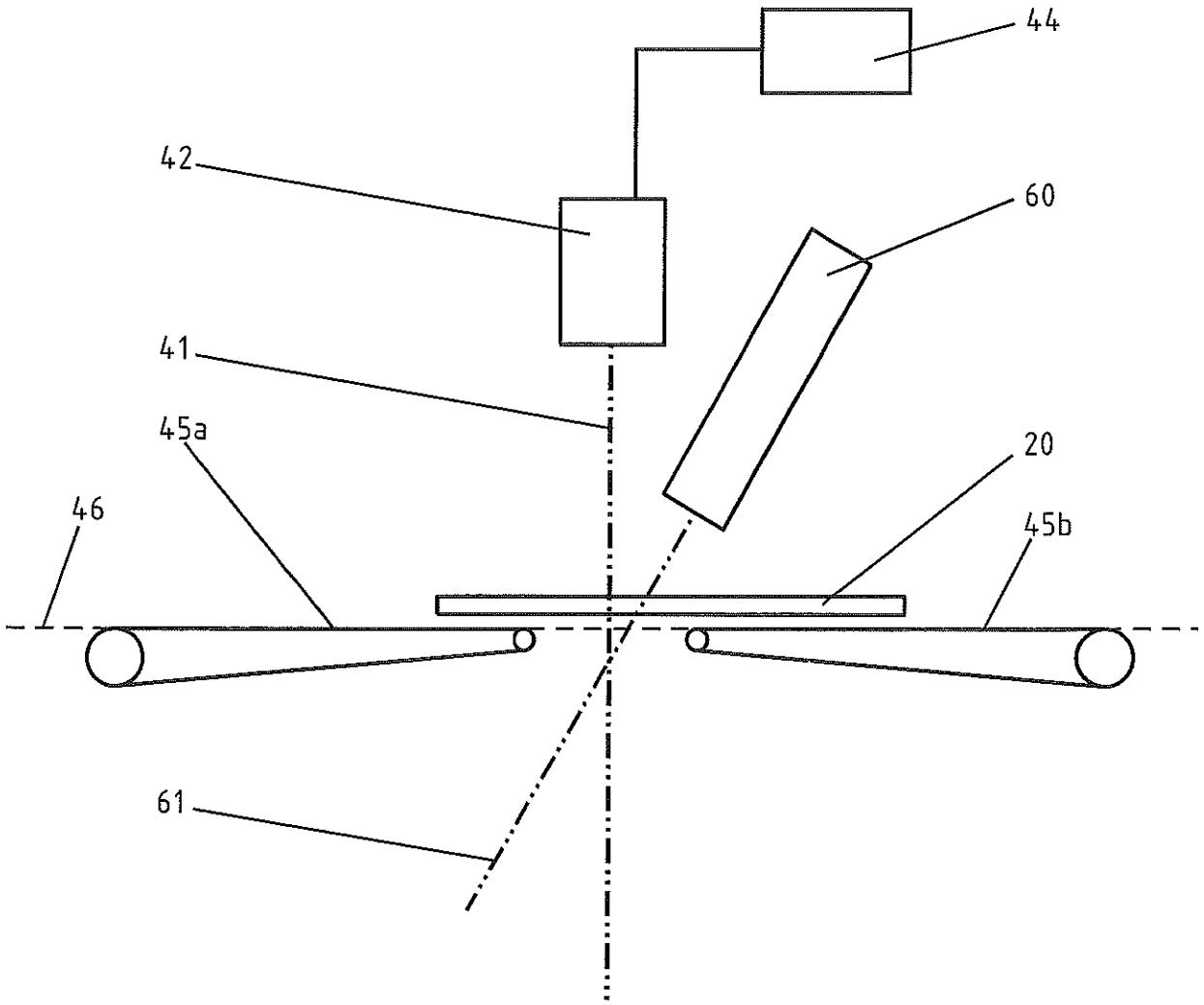


Fig. 7

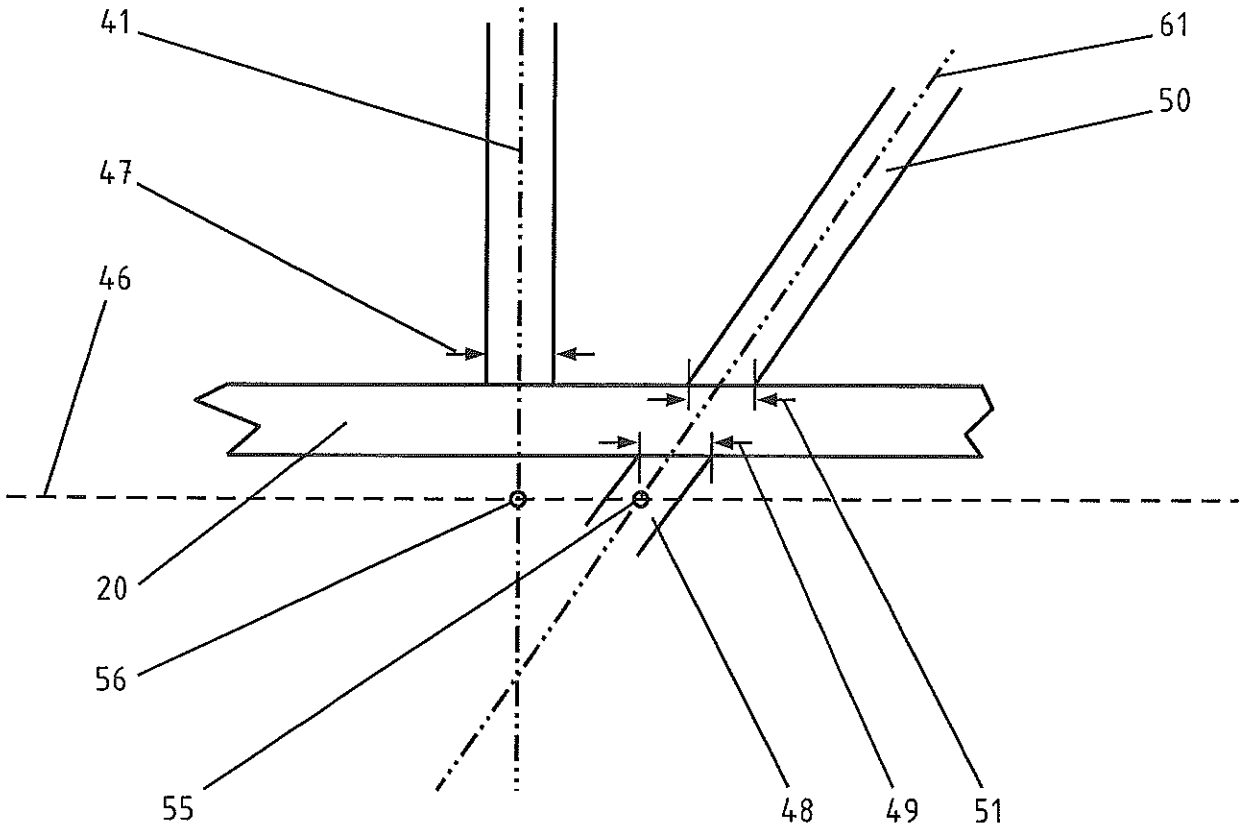


Fig. 8

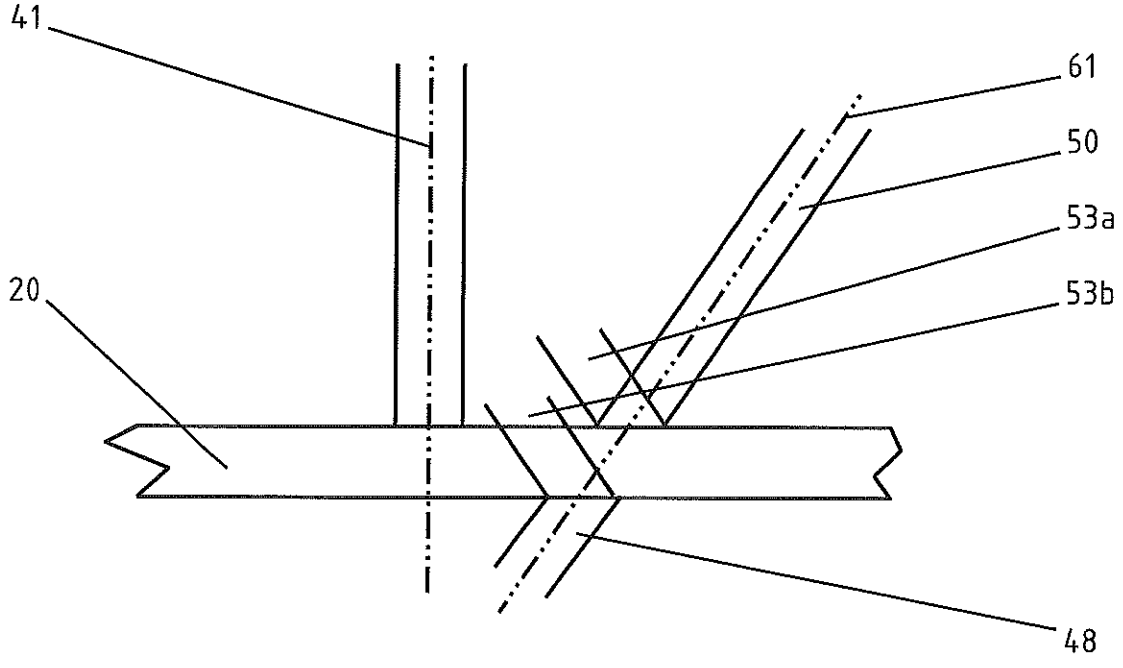


Fig. 9